

Phison Electronics Corporation

Embedded SSD Series Automotive PCIe NVMe SSD Specification (PS5021-E21T + Kioxia 112L 3D TLC) MPT560

Version 2.4



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Revision History

Revision	Draft Date	History	Author
2.0	2024/02/06	First Release	Eleven Tseng
2.1	2024/03/15	Revise Pin Assignment E13 naming	Eleven Tseng
2.2	2024/04/30	Revise the PN	Eleven Tseng
2.3	2024/06/07	Revise Power consumption	Eleven Tseng
		1. Revise PS4 (<2.5Mw) in Product Overview page	
2.4	2024/09/20	2. Revise Notes3 in MAX Current page	Eleven Tseng
		3. Revise warranty policy	



Product Overview

- Product Series: MPT560
- Capacity
 - 64GB, 128GB, 256GB, 512GB, 1024GB
- Form Factor
 - BGA type 1620, 16 mm x 20 mm
 - M.2 type 2230, 22mm x 30mm
- PCle Express Base Specification
 - Gen 4 x 4 lanes
 - NVMe 1.4
 - PCI Express Base 4.0
 - PCI Express M.2 Specification Revision 4.0, Version 1.0
- Performance¹
 - Read: up to 3650MB/s
 - Write: up to 2900MB/s
- Reliability
 - MTBF > 2 million hours (Mean Time Between Failure)
 - UBER < 1 sector per 10¹⁶ bits read (Uncorrectable Bit Error Rate)
- Package Compliant
 - RoHS
 - MSL3
- Voltage Supply Rails
 - BGA type 1620
 - P1=2.5V
 - P2=1.2V
 - P3=0.85V
 - M.2 type 2230 = 3.3V

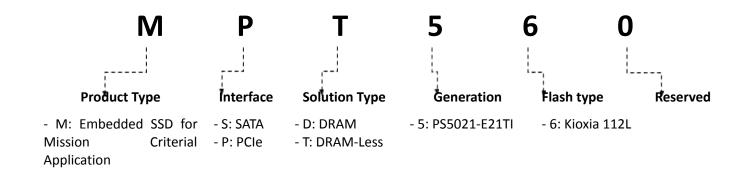
- Power Saving Modes (Optional)
 - PS0/ PS1/ PS2/ PS3/ PS4 (< 2.5W)
 - Support APST
 - Support ASPM
 - Support L1.2
- Endurance: Total Bytes Written (TBW)
 - Up to 1341TB for 1024GB
- Temperature Range²
 - Automotive Grade 2: -40°C ~ 105°C
 - Industrial Grade: -40°C ~ 85°C
- Features Support List:
 - Self-monitoring, analysis, and reporting technology (SMART)
 - Host-controlled thermal management
 - Power loss protection
 - End to end data path protection
 - Thermal throttling
 - LDPC + RAID ECC
 - SmartRefresh[™]
 - Support HMB(Host Memory Buffer)³
 (option support)
 - Support TCG OPAL(option support)⁴
 - RPMB
 - Boot Partition

NOTES:

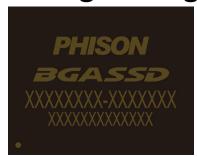
- 1. For more details on Performance, please refer to <u>Chapter 2</u>.
- 2. The operation temperature means the case temperature.
- 3. Win10 (version 1809) and above supports HMB (Host Memory Buffer) function.
- BGASSD 1620 type doesn't support PSID QR Code screen (if needed please contact to us)

Product Series Naming Rule





Package Inking



BGA Size	Grade	Part Number	Dimension	BGA	Flash mode	Density
		ESE3D211-64GA	16x20x1.15mm	291 Ball	1-CH	64GB
	Automotive	ESE3D222-X28A	16x20x1.15mm	291 Ball	2-CH	128GB
	Grade 2	ESE3D243-256A	16x20x1.15mm	291 Ball	4-CH	256GB
	(-40°C ~ 105°C)	ESE3D244-512A	16x20x1.35mm	291 Ball	4-CH	512GB
1620		ESE3D247-M24A	16x20x1.65mm	291 Ball	4-CH	1024GB
1620	Lo di satola l	ESE3D211-64GI	16x20x1.15mm	291 Ball	1-CH	64GB
		ESE3D222-X28I	16x20x1.15mm	291 Ball	2-CH	128GB
	Industrial	ESE3D243-256I	16x20x1.15mm	291 Ball	4-CH	256GB
	(-40°C ~ 85°C)	ESE3D244-512I	16x20x1.35mm	291 Ball	4-CH	512GB
		ESE3D247-M24I	16x20x1.65mm	291 Ball	4-CH	1024GB



Table of Contents

1.	INTRODUCTION	10
	1.1. General Description	10
	1.2. Controller Block Diagram	10
	1.3. Flash Management	11
	1.3.1. Error Correction Code (ECC)	11
	1.3.2. Wear Leveling	11
	1.3.3. Bad Block Management	11
	1.3.4. TRIM	11
	1.3.5. S.M.A.R.T.	12
	1.3.6. Over-Provision	12
	1.3.7. Firmware Upgrade	12
	1.4. Advanced Device Security Features	13
	1.4.1. Secure Erase	13
	1.5. SSD Lifetime Management	13
	1.5.1. Terabytes Written (TBW)	13
	1.5.2. Media Wear Indicator	13
	1.5.3. Read Only Mode (End of Life)	13
	1.6. An Adaptive Approach to Performance Tuning	14
	1.6.1. Throughput	14
	1.6.2. SLC Caching	14
2.	PRODUCT SPECIFICATIONS	15
3.	ENVIRONMENTAL SPECIFICATIONS	21
	3.1. MTBF	21
	3.2. Certification & Compliance	21
4.	ELECTRICAL SPECIFICATIONS	22
	4.1. Supply Voltage (BGA Type 1620)	22
	4.2. Power Consumption (BGA Type 1620)	22
	4.3. Supply Voltage (M.2 Type 2230)	24
	4.4. Power Consumption (M.2 Type 2230)	24
	4.5. Idle Power Consumption (M.2 Type 2230)	25
5.	INTERFACE	26
	5.1. BGA type 1620 Pin Assignment/Descriptions	26
	5.2. M.2 type 2230 Pin Assignment/Descriptions	35
6.	SUPPORTED COMMANDS	38
	6.1. NVMe Command List	38
	6.2. Identify Device Data	39
	6.3. SMART Attributes	45
7.	PHYSICAL DIMENSION	46
	7.1. BGA type 1620	46
	7.2. M.2 type 2230	50
8.	APPLICATION NOTES	52
	8.1. Wafer Level Chip Scale Packaging (WLCSP) Handling Precautions	52
	8.2. M Key M.2 SSD Assembly Precautions	52



9.	PRODUCT WARRANTY POLICY	53
10.	REFERENCE	54
11.	TERMINOLOGY	55



List of Figures

Figure 1-1 Controller Block Diagram	10
Figure 2-1 Thermal Throttling by On-die Thermal Sensor	18
Figure 5-1 BGA type 1620 Pin Assignment	26
Figure 5-2 M.2 PCIe SSD Pin Assignment	35
Figure 7-1 BGA type 1620 Package Outline Drawing	46
Figure 7-2 M.2 type 2230 Package Outline Drawing	51
Figure 8-1 M Key M.2 Assembly Precautions	52
List of Tables	
Table 2-1 User Capacity and Addressable Sectors	16
Table 2-2 Performance	16
Table 2-3 TBW	17
Table 2-4 APST	19
Table 3-1 MTBF	21
Table 4-1 Supply Voltage	22
Table 4-2 Kioxia 112L 3D TLC (1200MT/s) Power Consumption of each power state in mW	22
Table 4-3 Kioxia 112L 3D TLC (1200MT/s) PS0 (Full Speed Mode) MAX Current in mA	23
Table 4-4 Supply Voltage	24
Table 4-5 Kioxia 112L 3D TLC (1200MT/s) Power Consumption in mW	24
Table 4-6 Kioxia 112L 3D TLC (1200MT/s) Idle Power Consumption in mW	25
Table 5-1 BGA type 1620 Pin Description	27
Table 5-2 Pin Assignment and Description of MPT560 (PS5021-E21TI) M.2 2230	35
Table 6-1 Admin Commands	38
Table 6-2 Admin Commands – NVM Command Set Specific	38



Table 6-3 NVM Commands	38
Table 6-4 Identify Controller Data Structure	39
Table 6-5 SMART Attributes (Log Identifier 02h)	45
Table 7-1 BGA SSD Physical Dimensions and Weight	46
Table 7-2 Package Specification (Kioxia 112Layers 3D TLC x1/x2/x4 solution)	47
Table 7-3 Package Specification (Kioxia 112Layers 3D TLC x8 solution)	48
Table 7-4 Package Specification (Kioxia 112Layers 3D TLC x16 solution)	49
Table 7-5 M.2 type 2230 Physical Dimensions	50
Table 10-1 List of References	54
Table 11-1 List of Terminology	55

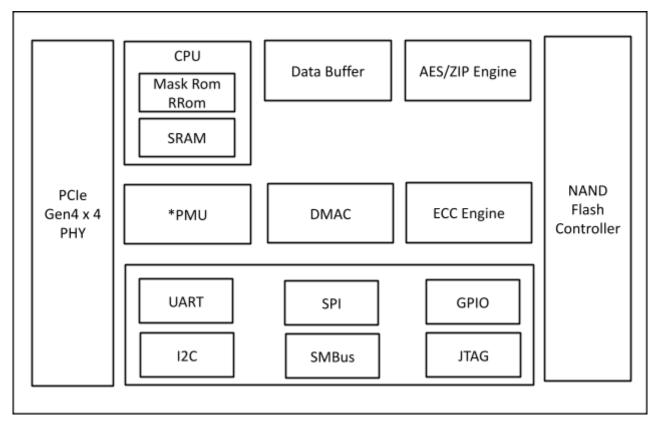
1. INTRODUCTION

1.1. General Description

Phison MPT560 (PS5021-E21TI) 1620 BGA SSD delivers all the advantages of flash drive technology with PCIe Gen 4x4 interface in an embedded BGA form factor. The MPT560 (PS5021-E21TI) 1620 BGA SSD could provide the capacity range from 64GB to 1024GB. It is estimated to reach up to 3650 MB/s read as well as 2900 MB/s write sequential performance. The MPT560 (PS5021-E21TI) 1620 BGA SSD throughput is capable of saturating Gen 4x4 host interface. Moreover, the power consumption of MPT560 (PS5021-E21TI) 1620 BGA SSD is much lower than traditional hard drives, making it the best embedded solution for new platforms.

1.2. Controller Block Diagram





^{*}PMU: Power management unit

Figure 1-1 Controller Block Diagram



1.3. Flash Management

1.3.1. Error Correction Code (ECC)

Flash memory cells will deteriorate with use, which might generate random bit errors in the stored data. Thus, MPT560 (PS5021-E21TI) 1620 PCIe BGA SSD applies the LDPC (Low Density Parity Check) of ECC algorithm, which can detect and correct errors occur during read process, ensure data been read correctly, as well as protect data from corruption.

1.3.2. Wear Leveling

NAND flash devices can only undergo a limited number of program/erase cycles, when flash media is not used evenly, some blocks get updated more frequently than others and the lifetime of device would be reduced significantly. Thus, wear leveling is applied to extend the lifespan of NAND flash by evenly distributing write and erase cycles across the media.

Phison provides advanced wear leveling algorithm, which can efficiently spread out the flash usage through the whole flash media area. Moreover, by implementing both dynamic and static wear leveling algorithms, the life expectancy of the NAND flash is greatly improved.

1.3.3. Bad Block Management

Bad blocks are blocks that do not function properly or contain more invalid bits causing stored data unstable, and their reliability is not guaranteed. Blocks that are identified and marked as bad by the manufacturer are referred to as "Early Bad Blocks". Bad blocks that are developed during the lifespan of the flash are named "Later Bad Blocks". Phison implements an efficient bad block management algorithm to detect the factory-produced bad blocks and manages bad blocks that appear with use. This practice prevents data being stored into bad blocks and further improves the data reliability.

1.3.4. TRIM

TRIM is a feature which helps improve the read/write performance and speed of solid state drives (SSD). SSDs are not able to overwrite existing data, so the available space gradually becomes smaller with each use. With the TRIM command, the operating system can inform the SSD so that blocks of data that are no



longer in use can be removed permanently. Thus, the SSD will perform the erase action, which prevents unused data from occupying blocks at all time.

1.3.5. S.M.A.R.T.

S.M.A.R.T., an acronym for Self-Monitoring, Analysis and Reporting Technology, is an open standard that allows a solid state drive to automatically detect its health and report potential failures. When a failure is recorded by S.M.A.R.T., users can choose to replace the drive to prevent unexpected outage or data loss. Moreover, S.M.A.R.T. can inform users impending failures while there is still time to perform proactive actions, such as save data to another device.

1.3.6. Over-Provision

Over Provisioning refers to the preserving additional area beyond user capacity in a SSD, which is not visible to users and cannot be used by them. However, it allows a SSD controller to utilize additional space for better performance and WAF. With Over Provisioning, the performance and IOPS (Input/ Output Operations per Second) are improved by providing the controller additional space to manage P/E cycles, which enhances the reliability and endurance as well. Moreover, the write amplification of the SSD becomes lower when the controller writes data to the flash.

1.3.7. Firmware Upgrade

Firmware can be considered as a set of instructions on how the device communicates with the host. Firmware will be upgradable when new features are added, compatibility issues are fixed, or read/write performance gets improved. Phison has its own secure firmware. The firmware codes are all RSA signed and are checked by download and boot ROM. Any unauthorized firmware cannot be loaded into our SSD.



1.4. Advanced Device Security Features

1.4.1. Secure Erase

Secure Erase is a standard NVMe format command and will make all "0xFF" to fully wipe all the data on hard drives and SSDs. When this command is issued, SSD controller will erase its storage blocks and return to its factory default settings.

1.5. SSD Lifetime Management

1.5.1. Terabytes Written (TBW)

TBW (Terabytes Written) is a measurement of SSDs' expected lifespan, which represents the amount of data written to the device. To calculate the TBW of a SSD, the following equation is applied:

TBW = [(NAND Endurance) x (SSD Capacity)] / [WAF]

NAND Endurance: NAND endurance refers to the P/E (Program/Erase) cycle of a NAND flash.

SSD Capacity: The SSD capacity is the specific capacity in total of a SSD.

<u>WAF</u>: Write Amplification Factor (WAF) is a numerical value representing the ratio between the amount of data that a SSD controller needs to write and the amount of data that the host's flash controller writes. A better WAF, which is near 1, guarantees better endurance and lower frequency of data written to flash memory.

TBW in this document is based on JEDEC 219 workload.

1.5.2. Media Wear Indicator

Actual life indicator reported by SMART Attribute byte index [5], Percentage Used, recommends User to replace drive when reaching to 100%.

1.5.3. Read Only Mode (End of Life)

When drive is aged by cumulated program/erase cycles, media worn-out may cause increasing numbers of later bad block. When the number of usable good blocks falls outside a defined usable range, the drive will notify Host through AER event and Critical Warning to enter Read Only Mode to prevent further data



corruption. User should start to replace the drive with another one immediately.



1.6. An Adaptive Approach to Performance Tuning

1.6.1. Throughput

Based on the available space of the disk, MPT560 (PS5021-E21TI) 1620 PCle BGA SSD will regulate the read/write speed and manage the performance of throughput. When there still remains a lot of space, the firmware will continuously perform read/write action. There is still no need to implement garbage collection to allocate and release memory, which will accelerate the read/write processing to improve the performance. Contrarily, when the space is going to be used up, MPT560 (PS5021-E21TI) 1620 PCle BGA SSD will slow down the read/write processing, and implement garbage collection to release memory. Hence, read/write performance will become slower.

1.6.2. SLC Caching

MPT560 (PS5021-E21TI) 1620 PCIe BGA SSD's firmware design currently adopts dynamic caching to deliver better performance for better endurance and consumer user experience.



2. PRODUCT SPECIFICATIONS

Product: MPT560

Capacity

- 64GB, 128GB, 256GB, 512GB, 1024GB
- Support 32-bit addressing mode

• Electrical/Physical Interface

- PCle Interface
- Compliant with NVMe 1.4
- PCIe Express Base ver. 4.0
- PCI Express M.2 Specification Revision 4.0, Version 1.0
- PCIe Gen 4 x 4 lane & backward compatible to PCIe Gen 3, PCIe Gen 2 and Gen 1
- Support up to QD 128 with queue depth of up to 64K
- Support power management

Supported NAND Flash

- Support up to 16 Flash Chip Enables (CE) within a single design
- Support 8-bit I/O NAND Flash
- Support Toggle 2.0, Toggle 3.0 and Toggle 4.0 interface
 - ♦ Kioxia 112-Layers 3D TLC

• ECC Scheme

MPT560 (PS5021-E21TI) 1620 BGA SSD applies the LDPC + RAID ECC algorithm.

• Sector Size Support

- 512byte
- 4KB

UART/GPIO

Voltage Rails

- BGASSD type 1620
 - P1=2.5V



- P2=1.2V
- P3=0.85V
- M.2 type 2230 = 3.3V
- Support SMART and TRIM commands

LBA Range

IDEMA standard

Table 2-1 User Capacity and Addressable Sectors

	512 Byte	es/Sector	4K Bytes/Sector		
Capacity	Number of Total	User Available	Number of Total	User Available Bytes	
	LBA	Bytes	LBA		
64GB	125,045,424	64,023,257,088	15,630,678	64,023,257,088	
128GB	250,069,680	128,035,676,160	31,258,710	128,035,676,160	
256GB	500,118,192	256,060,514,304	62,514,774	256,060,514,304	
512GB	1,000,215,216	512,110,190,592	125,026,902	512,110,190,592	
1024GB	2,000,409,264	1,024,209,543,168	250,051,158	1,024,209,543,168	

Performance

Kioxia 112Layers 3D TLC (1200MT/s) PS0 (Full Speed Mode)

Table 2-2 Performance

			Performance				
Compaitu	Flash Structure	65#	Sequential		Random		
Capacity		Flash Structure CE#	Read	Write	Read	Write	
			(MB/s)	(MB/s)	(IOPS)	(IOPS)	
64GB	64GB x 1	1	660	250	30K	53K	
128GB	64GB x 2	2	1400	510	60K	120K	
256GB	64GB x 4	4	2950	1000	110K	245K	
512GB	64GB x 8	8	3650	1900	220K	450K	
1024GB	64GB x 16	16	3650	2900	380K	500K	

- 1. Performance may differ according to flash configuration, use condition, environment and platform.
- 2. Use CrystalDiskMark 7.0.0 with QD8T1, 1GB range for sequential read/write test
- 3. Use IOmeter v1.1.0 with QD32T16, 1GB range for 4KB random read/write test.



- 4. Performance specification is under that Thermal Throttling has not worked yet.
- 5. CPU: AMD Ryzen 7 5800X 8-Core Processor
- 6. Operating System: Windows 10 Professional (x64)
- 7. Measurement environment: Room temperature: 20~25°C, humidity: 40~60%RH, DC+3.3V condition.

• TBW (Terabytes Written)

Table 2-3 TBW

Capacity	DWPD	
64GB	70	1
128GB	85	0.606
256GB	248	0.885
512GB	661	1.180
1024GB	1341	1.196

- 1. TBW is measured by JEDEC Client 219A workload and calculated with PE count = 3000. It may differ according to flash configuration and platform configuration.
- 2. DWPD (Drive Write Per Day) is calculated based on 3-year lifetime. DWPD = TBW / (365 days x 3 years x User Capacity)
- 3. The SSD supports trim function. If Operation System does not support trim command, performance and TBW will be affected. (Like certain Windows OS, Linux kernel version before 2.6.33, other OS please reference each own user manual)
- 4. The endurance of SSD could be estimated based on user behavior, NAND endurance cycles, and write amplification factor.



Thermal Throttling

The purpose of thermal throttling is to prevent any components in a SSD from over-heating during read and write operations. PS5021-E21T is designed with an on-die thermal sensor and with its accuracy, firmware can apply different levels of throttling to achieve the purpose of protection efficiently and proactively via S.M.A.R.T. reading.

Purpose of Thermal Throttling:

In order to keep the optimal performance in the safe range of the temperature.

– Thermal sensors:

We have on-die thermal sensor (inside the controller and NAND flash) to detect temperature.

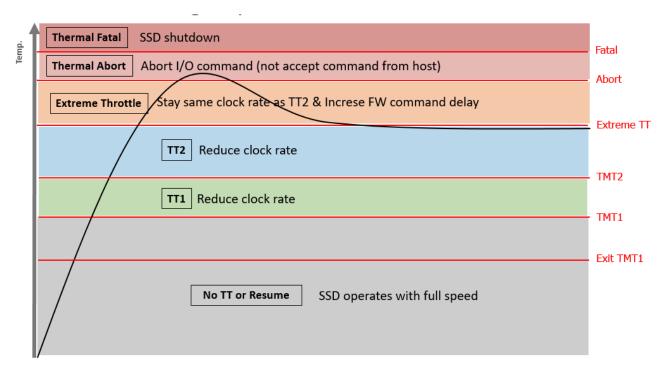


Figure 2-1 Thermal Throttling by On-die Thermal Sensor

• TCG Opal 2.0 (Option)

The Opal specification is a set of specifications for self-encrypting drives published by the Trusted Computing Group (TCG), a non-profit organization that develops, defines, and promotes standards and specifications for secure computing. The Opal Security Subsystem Class(SSC) 2.0 defines the details of



data management in storage devices and the classes authority for data access, and secures data from theft and tampering by unauthorized persons who are able to gain access to the storage device or host system.

TCG Opal 2.0 Main Features:

- AES 256-bitHardware Self Encryption
- Deploy Storage Device & Take Ownership: The Storage Device is integrated into its target system and ownership transferred by setting or changing the Storage Device's owner credential.
- Activate or Enroll Storage Device: LBA ranges are configured and data encryption and access control credentials (re)generated and/or set on the Storage Device. Access control is configured for LBA range unlocking.
- Lock & Unlock Storage Device: unlocking of one or more LBA ranges by the host and locking of those ranges under host control via either an explicit lock or implicit lock triggered by a reset event. MBR shadowing provides a mechanism to boot into a secure pre-boot authentication environment to handle device unlocking.
- Repurpose & End-of-Life: erasure of data within one or more

Autonomous Power State Transition(Option)

Device to support multiple power states. APST supports states where there is reduced power equating to slower performance or where the device is temporarily sleeping in a non-operational state and then woken up on activity. APST allows the transition between operational state (PSO/1/2) and non-operational states (PS3/4) automatically. Host can configure power state as below table:

Table 2-4 AF31					
Initial Power States	ITPS	ITPT (ms) *			
PS0	PS3	100			
PS1	PS3	100			
PS2	PS3	100			
PS3	PS4	9,900			

Table 2-4 APST

Notes:

- 1. Idle Transition Power State (ITPS): Transfer from Initial Power States to other Power States.
- 2. Idle Time Prior to Transition (ITPT): The waiting time that Initial Power States transfers to other Power States when device is idle.

Active State Power Management(Option)

Active-state power management (ASPM) is a power management mechanism for PCI Express devices. It is an autonomous hardware-based, active state mechanism that enables power savings even when the connected components are in the fully active state. Link Power Management State (L0, L1, L1.1, L1.2) can be controlled by ASPM. PCI Express defines the following Link power management states:

- L0: Active state
- LOs: A low resume latency, energy saving "standby" state.
- L1: Higher latency, lower power "standby" state.



- L1.1: Lite-energy-saving state.
- L1.2: Deep-energy-saving state.



3. ENVIRONMENTAL SPECIFICATIONS

3.1. MTBF

MTBF, Mean Time between Failures, is a measure of reliability of a device. Its value represents the average time between a repair and the next failure. The unit of MTBF is in hours. The higher the MTBF value, the higher the reliability of the device.

Our MTBF result is based on Telcorida methodology. Please note that a lower MTBF should be expected for higher capacity drives, and we apply the lowest MTBF for all capacities.

Table 3-1 MTBF

Capacity	MTBF
64GB	
128GB	
256GB	2 million hours
512GB	
1024GB	

3.2. Certification & Compliance

- RoHS
- WHQL
- PCI Express Base 4.0
- UNH-IOL NVM Express Logo



4. ELECTRICAL SPECIFICATIONS

4.1. Supply Voltage (BGA Type 1620)

Table 4-1 Supply Voltage

Parameter	Rating				
	Specification	Min.	Nom.	Max.	
Operating Voltage	Flash Core	+2.45V	+2.5V	+2.75V	
Operating Voltage	Flash IO supply	+1.16V	+1.2V	+1.26V	
	Controller Core	+0.80V	+0.85V	+0.88V	
Rise Time (Max/Min)	1.2ms/0.8ms				
Fall Time (Max/Min)	lin) Note ⁴				

NOTES:

- 1. Minimum time between power removed from SSD (V_{CC} < 500 mW) and power re-applied to the drive.
- 2. It shall be driven down Vcc to below 0.5V and stay low for at least 1ms before Vcc power up.
- 3. The Min. Off Time may differ according to power solution used.
- 4. Please follow PCI Express M.2 Specification: BGA SSD Voltage Supply Power-off Sequencing.

4.2. Power Consumption (BGA Type 1620)

Table 4-2 Kioxia 112L 3D TLC (1200MT/s) Power Consumption of each power state in mW

			- 1	, - ,						
Compaitu	Flash	CE#		Read			Write		DC3	DC4
Capacity	Structure	CE#	PS0	PS1	PS2	PS0	PS1	PS2	PS3	PS4
64GB	64GB x 1	1	1,750	1,465	1,250	1,550	1,250	1,200	50	2.5
128GB	64GB x2	2	2,065	1,800	1,250	1,650	1,350	1,200	50	2.5
256GB	64GB x 4	4	2,900	2,000	1,350	2,200	1,700	1,200	50	2.5
512GB	64GB x 8	8	3,200	2,200	1,300	2,650	1,700	1,200	50	2.5
1024GB	64GB x 16	16	3,500	2,100	1,300	3,500	1,800	1,200	50	2.5

- 1. Power consumption is estimated with the condition under ambient temperature @25°C.
- 2. The temperature of a storage device in PS1 should remain constant or should slightly decrease for all workloads so the actual power in PS1 should be lower than PS0.
- 3. The temperature of a storage device in PS2 should decrease sharply for all workloads so the actual power in PS2 should be lower than PS1.



Table 4-3 Kioxia 112L 3D TLC (1200MT/s) PS0 (Full Speed Mode) MAX Current in mA

Capacity	Flash Structure	CE#	PWR1 Max (mA)	PWR2 Max (mA)	PWR3 Max (mA)
64GB	64GB x 1	1	300	430	1,500
128GB	64GB x2	2	650	650	1,500
256GB	64GB x 4	4	970	1,000	1,500
512GB	64GB x 8	8	1,000	1,130	1,500
1024GB	64GB x 16	16	1,100	1,260	1,500

- 1. Power consumption is estimated with the condition under ambient temperature @25°C.
- 2. The Max value of power consumption is achieved based on 100% conversion efficiency.
- 3. Max current is estimated under burst performance



4.3. Supply Voltage (M.2 Type 2230)

Table 4-4 Supply Voltage

Parameter		Rating	
Operating Voltage	Min.	Nom.	Max.
Operating Voltage	+3.135V	+3.3V DC	+3.465V
Rise Time (Max/Min)		1.2ms/0.8ms	
Fall Time (Max/Min)		Note ⁴	

NOTES:

- 1. Minimum time between power removed from SSD (V_{cc} < 500 mW) and power re-applied to the drive.
- 2. It shall be driven down Vcc to below 0.5V and stay low for at least 1ms before Vcc power up.
- 3. The Min. Off Time may differ according to power solution used.
- 4. Please follow PCI Express M.2 Specification: BGA SSD Voltage Supply Power-off Sequencing.

4.4. Power Consumption (M.2 Type 2230)

Table 4-5 Kioxia 112L 3D TLC (1200MT/s) Power Consumption in mW

IE 4-3 KIUXIA	112L 3D 1LC (120	OIVI 1/3	Power	onsumption in i
Capacity	Flash Structure	CE#	Read	Write
64GB	64GB x 1	1	2050	1880
128GB	64GB x2	2	2460	2070
256GB	64GB x 4	4	3570	2670
512GB	64GB x 8	8	4000	3600
1024GB	64GB x 16	16	4230	4520

- 1. The measured power voltage of M.2 SSD is 3.3V.
- 2. Measurement environment: Room temperature: 20~25 °C, humidity: 40~60%RH, DC+3.3V condition.
- 3. Power consumption may differ according to flash configuration, use condition, environment and platform configuration.



4.5. Idle Power Consumption (M.2 Type 2230)

Table 4-6 Kioxia 112L 3D TLC (1200MT/s) Idle Power Consumption in mW

Capacit y	Flash Structure	CE #	Idle
64GB	64GB x 1	1	150 0
128GB	64GB x2	2	150 0
256GB	64GB x 4	4	150 0
512GB	64GB x 8	8	150 0
1024GB	64GB x 16	16	150 0

[Notes]

- 1. Idle power consumption is measured at idle state with no write/read operation.
- 2. The measured power voltage of M.2 SSD is 3.3V.
- 3. Measurement environment: Room temperature: 20~25 °C, humidity: 40~60%RH, DC+3.3V condition.
- 4. Power consumption may differ according to flash configuration, use condition, environment and platform configuration.



5. INTERFACE

5.1	ВС	iA t	ype	16	20 F	Pin .	Assi	ignr	nen	it/D	esc	ript	ion	S					
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	
A	DNU	DNU		DNU		DNU		DNU			DNU		DNU		DNU		DNU	DNU	A
В	DNU	DNU		DNU		DNU		1V8_RBG			DNU		DNU		DNU		DNU	DNU	В
С	GND	GND	GND	GND	GND	DNU	DNU	DNU	DNU	FLASH_RZQ	DNU	DNU	DNU	DNU	GND	DNU	DNU	DNU	С
D				REFCLKP	REFOLKN	GND	PERSTN	CLKREQE	PWR_1	PWR_1	GND	XEXTRISTS	DIAG1	DNU	DNU				D
E	GND	GND	GND	GND	GND	GND	GND	DNU	PWR_1	PWR_1	GND	DNU	DIAGO	GND	GND	DNU	DNU	DNU	E
F				PERP0	PER NO	GND								DNU	GND				F
G	GND	GND	GND	GND	GND		PWR_3	PWR_3	GND	GND	PWR_3	PWR_3		GND	GND	DNU	DNU	DNU	G
н				PETP)	PETN0		PWR_3	PWR_3	GND	GND	PWR_3	PWR_3		GND	PLN				Н
J	GND	GND	GND	GND	GND		PWR_3	PWR_3	GND	GND	PWR_3	PWR_3		GND	GND	DNU	DNU	DNU	J
к				PERP1	PERN1		GND	GND	GND	GND	GND	GND		DNU	PLA				к
L	GND	GND	GND	GND	GND		DNU	DNU	DNU	DNU	DNU	DNU		GND	GND	DNU	DNU	DNU	L
М				PETP1	PETN1		DNU	DNU	GND	GND	DNU	DNU		DNU	DNU				М
N	GND	GND	GND	GND	GND		DNU	DNU	DNU	DNU	DNU	DNU		GND	GND	DNU	JTAG_TCK	JTAG_TMS	N
P				PERP2	PERN2		GND	GND	GND	GND	GND	GND		DNU	DNU				P
R	GND	GND	GND	GND	GND		PWR_2	PWR_2	GND	GND	PWR_2	PWR_2		GND	GND	DNU	XGPIO0	DNU	R
т				РЕТР2	PETN2		PWR_2	PWR_2	GND	GND	PWR_2	PWR_2		DNU	DNU				T
U	GND	GND	GND	GND	GND		PWR_2	PWR_2	GND	GND	PWR_2	PWR_2		GND	GND	DNU	SMB_CLK	SMB_DATA	U
v				PER P3	PERNS									DNU	DNU				v
w	GND	GND	GND	GND	GND	GND	LED/DAS	DNU	PWR_1	PWR_1	GND	DNU	DNU	GND	GND	DNU	DNU	DNU	w
Υ				РЕТРЗ	PETN3	GND	DNU	DNU	PWR_1	PWR_1	GND	DNU	GND	DNU	DNU				Y
AA	GND	GND	GND	GND	GND	DNU	DNU	DNU	DNU	CTL_RZQ	DNU	DNU	DNU	GND	GND	DNU	DNU	DNU	AA
AB	DNU	DNU		DNU		DNU		DNU			DNU		DNU		DNU		DNU	DNU	AB
AC	DNU	DNU		DNU		DNU		DNU			DNU		DNU		DNU		DNU	DNU	AC
	1	. 2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	

Figure 5-1 BGA type 1620 Pin Assignment



Table 5-1 BGA type 1620 Pin Description

		Table 5	-1 BGA type 1620 Pin Description	
Pin Name	BGA 291	Pin Type	Description	IO Voltage
	•		UART/GPIO	
XGPIO0	R17	1	Debug only	1.8V
DIAG1	D13	- 1	Debug only	1.8V
DIAG0	E13	0	Debug only	1.8V
SMB_CLK	U17	1/0	Debug only	1.8V
SMB_DATA	U18	1/0	Debug only	1.8V
JTAG_TCK	N17	I/O	Debug only	1.8V
JTAG_TMS	N18	I/O	Debug only	1.8V
XEXTRSTB	D12	-	Debug only	1.8V
1V8_REG	B8	-	Debug only	1.8V
		-	PCle Interface Signals	-
PERP0	F4			
PERN0	F5			
PERP1	K4	1		
PERN1	K5	1		
PERP2	P4	1		
PERN2	P5	1		
PERP3	V4	1		
PERN3	V5	i	PCIe TX/RX Differential signals defined by the PCI Express	
PETP0	H4	I/O	Card Electromechanical Specification.	
PETN0	H5			
PETP1	M4			
PETN1	M5			
PETP2	T4			
PETN2	T5			
PETP3	Y4			
PETN3	Y5			
REFCLKP	D4	I	PCIe Reference Clock signals (100 MHz) defined by the PCI	
REFCLKN	D5	I	Express Card Electromechanical Specification.	
PERSTN	D7	1	PCIe Reset is a functional reset to the card as defined by the PCI Express Mini Card Electromechanical Specification	1.8V
CLKREQB	D8	I/O	Clock Request is a reference clock request signal as defined by the PCI Express Mini Card Electromechanical Specification; Also used by L1 PM Substates.	1.8V



			Optional Signals	
FLASH_RZQ	C10	I	Flash Calibration REF RESISTENCE	-
CTL_RZQ	AA10	I	CTL Calibration REF RESISTENCE	-
PLA	K15	0	Power Loss Acknowledge	1.8V
PLN	H15	I	Power Loss Notification	1.8V
	•		SSD Specific Signals	
LED/DAS#	W7	0	Open drain, active low signal. This signal is used to allow the Adapter to provide status indication via LED device that will be provided by the system.	3.3V
	•	•	Power Supply Signals	
	D9			
	D10	1		
	E9	1		
DIAID 1	E10	1 .	254	0.5
PWR_1	W9		+2.5 V source	2.5V
	W10	1		
	Y9	1		
	Y10	1		
	R7			
	R8	1		
	R11	1		
	R12	1		
	T7	1		
	Т8	1		
PWR_2	T11	1 '	+1.2 V source	1.2V
	T12	1		
	U7	1		
	U8	1		
	U11	1		
	U12	1		
	G 7			
	G8	1		
	G11	1		
	G12	1		
PWR_3	H7		+0.85 V source	0.85\
	H8	1		
	H11	1		



Pin Name	BGA 291	Description	
	J12		
	J11		
	J8		
	J7		
	H12		



	C1	
	C2	
	C3	
	C4	
	C5	
	C15	
	D6	
	D11	
GND	E1	GND
	E2	
	E3	
	E4	
	E5	
	E6	
	E7	
	E11	
	E14	
	E15	
	F6	
	F15	
	G1	
	G2	
	G3	
	G4	
	G5	
	G9	
	G10	
	G14	
	G15	
	H9	
GND	H10	GND
GND	H14	GND
	J1	
	J2	
	J3	
	J4	
	J5	



	J9	
	J10	
	J14	
	J15	
	K7	
	K8	
	К9	
	K10	
	K11	
	K12	
	L1	
	L2	
	L3	
	L4	
	L5	
	L14	
	L15	
	M9	
	M10	
	N1	
	N2	
GND	N3	GND
	N4	
	N5	
	N14	
	N15	
	P7	
	P8	
	P9	
	P10	
	P11	
	P12	
	R1	
	R2	
	R3	
	R4	
	R5	



R9 R10 R14 R15 T9 T10 U1 U2 U3 U4 U5 U9 U10 U14 U15
R14 R15 T9 T10 U1 U2 U3 U4 U5 U9 U10 U14
R15 T9 T10 U1 U2 U3 U4 U5 U9 U10 U14
T9 T10 U1 U2 U3 U4 U5 U9 U10 U14
T10 U1 U2 U3 U4 U5 U9 U10 U14
U1 U2 U3 U4 U5 U9 U10 U14
U1 U2 U3 U4 U5 U9 U10 U14
U2 U3 U4 U5 U9 U10 U14
U3 U4 U5 U9 U10 U14
U4 U5 U9 U10 U14
U5 U9 U10 U14
U9 U10 U14
U10 U14
U14
1115
013
W1
W2
W3
W4
W5
W6
W11
W14
W15
Y6
Y11
Y13
AA1
AA2
AA3
AA4
AA5
AA14



DNU	A1	Do not use. Manufacturing purpose only
	A2	
	A4	
	A6	
	A8	
	A11	
	A13	
	A15	
	A17	
	A18	
DNU	B1	Do not use. Manufacturing purpose only
	B2	
	B4	
	B6	
	B11	
	B13	
	B15	
	B17	
	B18	
	C 6	
	C7	
	C8	
	C 9	
	C11	
	C12	
	C13	
	C14	
	C16	
	C17	
	C18	
	D14	
	D15	
	E8	
	E12	
	E16	
	E17	
	E18	



DNU	F14	Do not use. Manufacturing purpose only		
2.10	G16	Do not use. Manufacturing purpose only		
	G17			
	G18			
	J16			
	J17			
	J18			
	K14			
	L7			
	L8			
	L9			
	L10			
	L11			
	L12			
	L16			
	L17			
	L18			
	M7			
	M8			
	M11			
	M12			
	M14			
	M15			
	N7			
	N8			
	N9			
DNU	N10	Do not use. Manufacturing purpose only		
	N11			
	N12			
	N16			
	P14			
	P15			
	R16			
	R18			
	T14			
	T15			
	U16			



V14	
V15	
W8	
W12	
W13	
W16	
W17	
W18	
Y7	
Y8	
Y12	
Y14	
Y15	
AA6	
AA7	
AA8	
AA9	
AA11	
AA12	
AA13	
AA16	
AA17	
AA18	
AB1	
AB2	
AB4	
AB6	
AB8	
AB11	
AB13	
AB15	
AB17	
AB18	
AC1	
AC2	
AC4	
AC6	



AC8
AC11
AC13
AC15
AC17
AC18

5.2. M.2 type 2230 Pin Assignment/Descriptions

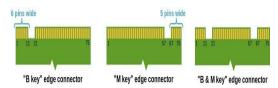


Figure 5-2 M.2 PCIe SSD Pin Assignment

Table 5-1 defines the signal assignment of the internal NGFF connector for SSD usage, described in the PCI Express M.2 Specification version 1.0 of the PCI-SIG.

Table 5-2 Pin Assignment and Description of MPT560 (PS5021-E21TI) M.2 2230

Pin#	PCle Pin	Description	
1	CONFIG_3 = GND	Ground	
2	3.3V	3.3V source	
3	GND	Ground	
4	3.3V	3.3V source	
5	PETn3	PCIe TX Differential signal defined by the PCI Express M.2 spec	
6	N/C	No Connect	
7	PETp3	PCIe TX Differential signal defined by the PCI Express M.2 spec	
8	PLN# (I)(0/3.3V)	Power Loss Notification	
9	GND	Ground	
10	LED1#	Open drain, active low signal. These signals are used to allow the add-in card to provide status indicators via LED devices that will be provided by the system.	
11	PERn3	PCIe RX Differential signal defined by the PCI Express M.2 spec	
12	3.3V	3.3V source	
13	PERp3	PCIe RX Differential signal defined by the PCI Express M.2 spec	
14	3.3V	3.3V source	
15	GND	Ground	
16	3.3V	3.3V source	
17	PETn2	PCIe TX Differential signal defined by the PCI Express M.2 spec	
18	3.3V	3.3V source	



19	PETp2	PCIe TX Differential signal defined by the PCI Express M.2 spec	
20	N/C	No connect	
21	GND	Ground	
22	N/C	No connect	
23	PERn2	PCIe RX Differential signal defined by the PCI Express M.2 spec	
24	N/C	No connect	
25	PERp2	PCIe RX Differential signal defined by the PCI Express M.2 spec	
26	N/C	No connect	
27	GND	Ground	
28	N/C	No connect	
29	PETn1	PCIe TX Differential signal defined by the PCI Express M.2 spec	
30	PLA_S3# (O)(0/3.3V)	Power Loss Acknowledge; Open Drain with pull-up on platform	
31	PETp1	PCIe TX Differential signal defined by the PCI Express M.2 spec	
32	N/C	No connect	
33	GND	Ground	
34	N/C	No connect	
35	PERn1	PCIe RX Differential signal defined by the PCI Express M.2 spec	
36	N/C	No connect	
37	PERp1	PCIe RX Differential signal defined by the PCI Express M.2 spec	
38	N/C	No connect	
39	GND	Ground	
40	SMB_CLK (I/O)(0/1.8V)	SMBus Clock; Open Drain with pull-up on platform	
41	PETn0	PCIe TX Differential signal defined by the PCI Express M.2 spec	
42	SMB_DATA (I/O)(0/1.8V)	SMBus Data; Open Drain with pull-up on platform.	
43	РЕТр0	PCIe TX Differential signal defined by the PCI Express M.2 spec	
44	ALERT#(O) (0/1.8V)	Alert notification to master; Open Drain with pull-up on platform; Active low.	
45	GND	Ground	
46	N/C	No connect	
47	PERn0	PCIe RX Differential signal defined by the PCI Express M.2 spec	
48	N/C	No connect	
49	PERp0	PCIe RX Differential signal defined by the PCI Express M.2 spec	
50	PERST#(I)(0/3.3V)	PE-Reset is a functional reset to the card as defined by the PCIe Mini CEM specification.	
51	GND	Ground	
52	CLKREQ#(I/O)(0/3 .3V)	Clock Request is a reference clock request signal as defined by the PCIe Mini CEM specification; Also used by L1 PM Sub-states.	
53	REFCLKn	PCIe Reference Clock signals (100 MHz) defined by the PCI Express M.2 spec.	



	PEWAKE#(I/O)(0/	PCIe PME Wake	
54	3.3V)	Open Drain with pull up on platform; Active Low.	
55	REFCLKp	PCIe Reference Clock signals (100 MHz)	
	•	defined by the PCI Express M.2 spec.	
Reserved for		Manufacturing Data line. Used for SSD manufacturing only.	
56	MFG DATA	Not used in normal operation.	
		Pins should be left N/C in platform Socket.	
57	GND	Ground	
	Decembed for	Manufacturing Clock line. Used for SSD manufacturing only.	
58	Reserved for	Not used in normal operation.	
	MFG CLOCK	Pins should be left N/C in platform Socket.	
59	Module Key M	Module Key	
60	Module Key M	Module Key	
61	Module Key M	Module Key	
62	Module Key M	Module Key	
63	Module Key M	Module Key	
64	Module Key M	Module Key	
65	Module Key M	Module Key	
66	Module Key M	Module Key	
67	N/C	No Connect	
68	SUSCLK(32KHz) (I)(0/3.3V)	No connect	
69	N/C	CONFIG_1 = No connect	
70	3.3V	3.3V source	
71	GND	Ground	
72	3.3V	3.3V source	
73	GND	Ground	
74	3.3V	3.3V source	
75	GND	CONFIG_2 = Ground	



6. SUPPORTED COMMANDS

6.1. NVMe Command List

Table 6-1 Admin Commands

lable 0-1 Admin Commands		
Opcode	Command Description	
00h	Delete I/O Submission Queue	
01h	Create I/O Submission Queue	
02h	Get Log Page	
04h	Delete I/O Completion Queue	
05h	Create I/O Completion Queue	
06h	Identify	
08h	Abort	
09h	Set Features	
0Ah	Get Features	
0Ch	Asynchronous Event Request	
0Dh	Namespace Management	
10h	Firmware Activate	
11h	Firmware Image Download	
14h	Device Self-test	
15h	Namespace Attachment	
18h	Keep Alive	

Table 6-2 Admin Commands – NVM Command Set Specific

Opcode	Command Description
80h	Format NVM
81h	Security Send
82h	Security Receive
84h	Sanitize

Table 6-3 NVM Commands

Opcode	Command Description
00h	Flush
01h	Write
02h	Read
04h	Write Uncorrectable
05h	Compare
08h	Write Zeroes
09h	Dataset Management

6.2. Identify Device Data

The following table details the sector data returned by the IDENTIFY DEVICE command.

Table 6-4 Identify Controller Data Structure

Bytes	Description	Default Value
01:00	PCI Vendor ID (VID)	0x1987
03:02	PCI Subsystem Vendor ID (SSVID)	0x1987
23:04	Serial Number (SN)	SN
63:24	Model Number (MN)	Model Number



Bytes	Description	Default Value
71:64	Firmware Revision (FR)	FW Name
72	Recommended Arbitration Burst (RAB)	0x4
75:73	IEEE OUI Identifier (IEEE)	Assigned by IEEE/RAC
76	Controller Multi-Path I/O and Namespace Sharing Capabilities (CMIC)	0x0
77	Maximum Data Transfer Size (MDTS)	0x6
79:78	Controller ID (CNTLID)	0x0
83:80	Version (VER)	0x10400
87:84	RTD3 Resume Latency (RTD3R)	0x186A0
91:88	RTD3 Entry Latency (RTD3E)	0x4C4B40
95:92	Optional Asynchronous Events Supported (OAES)	0x0
99:96	Controller Attributes (CTRATT)	0x2
101:100	Read Recovery Levels Supported (RRLS)	0x0
110:102	Reserved	0x00
111	Controller Type (CNTRLTYPE)	0x1
127:112	FRU Globally Unique Identifier (FGUID)	0x00
129:128	Command Retry Delay Time 1 (CRDT1)	0x0
131:130	Command Retry Delay Time 2 (CRDT2)	0x0
133:132	Command Retry Delay Time 3 (CRDT3)	0x0
239:134	Reserved	0x00
255:240	Refer to the NVMe Management Interface Specification for Definition	0x00
257:256	Optional Admin Command Support (OACS)	0x17
258	Abort Command Limit (ACL)	0x3
259	Asynchronous Event Request Limit (AERL)	0x7
260	Firmware Updates (FRMW)	0x12
261	Log Page Attributes (LPA)	0x1E
262	Error Log Page Entries (ELPE)	0xFE
263	Number of Power States Support (NPSS)	0x4
264	Admin Vendor Specific Command Configuration (AVSCC)	0x1
265	Autonomous Power State Transition Attributes (APSTA)	0x1
267:266	Warning Composite Temperature Threshold (WCTEMP)	0x17D
269:268	Critical Composite Temperature Threshold (CCTEMP)	0x17F
271:270	Maximum Time for Firmware Activation (MTFA)	0x64
275:272	Host Memory Buffer Preferred Size (HMPRE)	0x0 (HMB off) Depend on Disk Size(HMB on)
279:276	Host Memory Buffer Minimum Size (HMMIN)	0x0(HMB off) Depend on Disk Size(HMB on)
295:280	Total NVM Capacity (TNVMCAP)	By capacity
311:296	Unallocated NVM Capacity (UNVMCAP)	0x00
315:312	Replay Protected Memory Block Support (RPMBS)	0x1F0002
317:316	Extended Device Self-test Time (EDSTT)	0x1E
318	Device Self-test Options (DSTO)	0x0
319	Firmware Update Granularity (FWUG)	0x4
321:320	Keep Alive Support (KAS)	0x0
323:322	Host Controlled Thermal Management Attributes (HCTMA)	0x1
325:324	Minimum Thermal Management Temperature (MNTMT)	0x111
327:326	Maximum Thermal Management Temperature (MXTMT)	0x170
331:328	Sanitize Capabilities (SANICAP)	0xA0000002



Bytes	Doccrintian	Default Value
335:332	Description Host Mamory Buffor Minimum Descriptor Entry Size (HMMINDS)	0x400
337:336	Host Memory Buffer Minimum Descriptor Entry Size (HMMINDS) Host Memory Maximum Descriptors Entries (HMMAXD)	0x400 0x10
339:338	NVM Set Identifier Maximum (NSETIDMAX)	0x0
341:340		0x0
	Endurance Group Identifier Maximum (ENDGIDMAX)	
342	ANA Transition Time (ANATT)	0x0
343	Asymmetric Namespace Access Capabilities (ANACAP)	0x0
347:344	ANA Group Identifier Maximum (ANAGRPMAX)	0x0
351:348	Number of ANA Group Identifiers (NANAGRPID)	0x0
355:352	Persistent Event Log Size (PELS)	0x60
511:356	Reserved	0x00
512	Submission Queue Entry Size (SQES)	0x66
513	Completion Queue Entry Size (CQES)	0x44
515:514	Maximum Outstanding Commands (MAXCMD)	0x100
519:516	Number of Namespaces (NN)	0x1
521:520	Optional NVM Command Support (ONCS)	0xD7
523:522	Fused Operation Support (FUSES)	0x0
524	Format NVM Attributes (FNA)	0x0
525	Volatile Write Cache (VWC)	0x7
527:526	Atomic Write Unit Normal (AWUN)	0xFF
529:528	Atomic Write Unit Power Fail (AWUPF)	0x0
530	NVM Vendor Specific Command Configuration (NVSCC)	0x1
531	Reserved	0x0
533:532	Atomic Compare & Write Unit (ACWU)	0x0
535:534	Reserved	0x00
539:536	SGL Support (SGLS)	0x0
543:540	Maximum Number of Allowed Namespaces (MNAN)	0x0
767:544	Reserved	0x00
1023:768	NVM Subsystem NVMe Qualified Name (SUBNQN)	nqn.2020-11.org.nvmexp ress:uuid: (SN)
1791:1024	Reserved	0x00
2047:1792	Refer to the NVMe over Fabrics specification	0x00
2079:2048	Power State 0 Descriptor (PSD0)	
Bit[255:184]	Reserved	0x00
Bit[183:182]	Active Power Scale (APS)	0x0
Bit[181:179]	Reserved	0x0
Bit[178:176]	Active Power Workload (APW)	0x0
Bit[175:160]	Active Power (ACTP)	0x0
Bit[159:152]	Reserved	0x0
Bit[151:150]	Idle Power Scale (IPS)	0x0
Bit[149:144]	Reserved	0x0
Bit[143:128]	Idle Power (IDLP)	0x0
Bit[127:125]	Reserved	0x0
Bit[124:120]	Relative Write Latency (RWL)	0x0
Bit[119:117]	Reserved	0x0
Bit[116:112]	Relative Write Throughput (RWT)	0x0
Bit[111:109]	Reserved	0x0
Bit[108:104]	Relative Read Latency (RRL)	0x0
Bit[103:101]	Reserved	0x0
Bit[100:96]	Relative Read Throughput (RRT)	0x0
Bit[95:64]	Exit Latency (EXLAT)	0x0
J. 1, J J. 1, J		1



Bytes	Description	Default Value
Bit[63:32]	Entry Latency (ENLAT)	0x0
Bit[31:26]	Reserved	0x0
Bit[25]	Non-Operational State (NOPS)	0x0
Bit[24]	Max Power Scale (MPS)	0x0
Bit[23:16]	Reserved	0x0
Bit[15:0]	Maximum Power (MP)	0x1F4
2111:2080	Power State 1 Descriptor (PSD1)	·
Bit[255:184]	Reserved	0x00
Bit[183:182]	Active Power Scale (APS)	0x0
Bit[181:179]	Reserved	0x0
Bit[178:176]	Active Power Workload (APW)	0x0
Bit[175:160]	Active Power (ACTP)	0x0
Bit[159:152]	Reserved	0x0
Bit[151:150]	Idle Power Scale (IPS)	0x0
Bit[149:144]	Reserved	0x0
Bit[143:128]	Idle Power (IDLP)	0x0
Bit[127:125]	Reserved	0x0
Bit[124:120]	Relative Write Latency (RWL)	0x1
Bit[119:117]	Reserved	0x0
Bit[116:112]	Relative Write Throughput (RWT)	0x1
Bit[111:109]	Reserved	0x0
Bit[108:104]	Relative Read Latency (RRL)	0x1
Bit[103:101]	Reserved	0x0
Bit[100:96]	Relative Read Throughput (RRT)	0x1
Bit[95:64]	Exit Latency (EXLAT)	0x0
Bit[63:32]	Entry Latency (ENLAT)	0x0
Bit[31:26]	Reserved	0x0
Bit[25]	Non-Operational State (NOPS)	0x0
Bit[24]	Max Power Scale (MPS)	0x0
Bit[23:16]	Reserved	0x0
Bit[15:0]	Maximum Power (MP)	0xF0
2143:2112	Power State 2 Descriptor (PSD2)	
Bit[255:184]	Reserved	0x00
Bit[183:182]	Active Power Scale (APS)	0x0
Bit[181:179]	Reserved	0x0
Bit[178:176]	Active Power Workload (APW)	0x0
Bit[175:160]	Active Power (ACTP)	0x0
Bit[159:152]	Reserved	0x0
Bit[151:150]	Idle Power Scale (IPS)	0x0
Bit[149:144]	Reserved	0x0
Bit[143:128]	Idle Power (IDLP)	0x0
Bit[127:125]	Reserved	0x0
Bit[124:120]	Relative Write Latency (RWL)	0x2
Bit[119:117]	Reserved	0x0
Bit[116:112]	Relative Write Throughput (RWT)	0x2
Bit[111:109]	Reserved	0x0
Bit[108:104]	Relative Read Latency (RRL)	0x2
Bit[103:101]	Reserved	0x0
Bit[100:96]	Relative Read Throughput (RRT)	0x2
Bit[95:64]	Exit Latency (EXLAT)	0x0



Bytes	Description	Default Value
Bit[63:32]	Entry Latency (ENLAT)	0x0
Bit[31:26]	Reserved	0x0
Bit[25]	Non-Operational State (NOPS)	0x0
Bit[24]	Max Power Scale (MPS)	0x0
Bit[23:16]	Reserved	0x0
Bit[15:0]	Maximum Power (MP)	0xBE
2175:2144	Power State 3 Descriptor (PSD3)	•
Bit[255:184]	Reserved	0x00
Bit[183:182]	Active Power Scale (APS)	0x0
Bit[181:179]	Reserved	0x0
Bit[178:176]	Active Power Workload (APW)	0x0
Bit[175:160]	Active Power (ACTP)	0x0
Bit[159:152]	Reserved	0x0
Bit[151:150]	Idle Power Scale (IPS)	0x0
Bit[149:144]	Reserved	0x0
Bit[143:128]	Idle Power (IDLP)	0x0
Bit[127:125]	Reserved	0x0
Bit[124:120]	Relative Write Latency (RWL)	0x3
Bit[119:117]	Reserved	0x0
Bit[116:112]	Relative Write Throughput (RWT)	0x3
Bit[111:109]	Reserved	0x0
Bit[108:104]	Relative Read Latency (RRL)	0x3
Bit[103:101]	Reserved	0x0
Bit[100:96]	Relative Read Throughput (RRT)	0x3
Bit[95:64]	Exit Latency (EXLAT)	0x7D0
Bit[63:32]	Entry Latency (ENLAT)	0x1770
Bit[31:26]	Reserved	0x0
Bit[25]	Non-Operational State (NOPS)	0x1
Bit[24]	Max Power Scale (MPS)	0x1
Bit[23:16]	Reserved	0x0
Bit[15:0]	Maximum Power (MP)	0x1F4
2207:2176	Power State 4 Descriptor (PSD4)	
Bit[255:184]	Reserved	0x00
Bit[183:182]	Active Power Scale (APS)	0x0
Bit[181:179]	Reserved	0x0
Bit[178:176]	Active Power Workload (APW)	0x0
Bit[175:160]	Active Power (ACTP)	0x0
Bit[159:152]	Reserved	0x0
Bit[151:150]	Idle Power Scale (IPS)	0x0
Bit[149:144]	Reserved	0x0
Bit[143:128]	Idle Power (IDLP)	0x0
Bit[127:125]	Reserved	0x0
Bit[124:120]	Relative Write Latency (RWL)	0x4
Bit[119:117]	Reserved	0x0
Bit[116:112]	Relative Write Throughput (RWT)	0x4
Bit[111:109]	Reserved	0x0
Bit[108:104]	Relative Read Latency (RRL)	0x4
Bit[103:101]	Reserved	0x0
Bit[100:96]	Relative Read Throughput (RRT)	0x4
Bit[95:64]	Exit Latency (EXLAT)	0x9C40



Bytes	Description	Default Value
Bit[63:32]	Entry Latency (ENLAT)	0x2710
Bit[31:26]	Reserved	0x0
Bit[25]	Non-Operational State (NOPS)	0x1
Bit[24]	Max Power Scale (MPS)	0x1
Bit[23:16]	Reserved	0x0
Bit[15:0]	Maximum Power (MP)	0x32
	(N/A)	0
3071:3040	Power State 31 Descriptor (PSD31)	0
3107:3072	Vendor Specific (VS)	0x00
3109:3108	PLP Supported	0x8001
4095:3110	Vendor Specific (VS)	0x00



6.3. SMART Attributes

Table 6-5 SMART Attributes (Log Identifier 02h)

Bytes Index	Bytes	Description
[0]	1	Critical Warning
[2:1]	2	Composite Temperature
[3]	1	Available Spare
[4]	1	Available Spare Threshold
[5]	1	Percentage Used
[31:6]	26	Reserved
[47:32]	16	Data Units Read
[63:48]	16	Data Units Written
[79:64]	16	Host Read Commands
[95:80]	16	Host Write Commands
[111:96]	16	Controller Busy Time
[127:112]	16	Power Cycles
[143:128]	16	Power On Hours
[159:144]	16	Unsafe Shutdowns
[175:160]	16	Media and Data Integrity Errors
[191:176]	16	Number of Error Information Log Entries
[195:192]	4	Warning Composite Temperature Time
[199:196]	4	Critical Composite Temperature Time
[201:200]	2	Temperature Sensor 1
[203:202]	2	Temperature Sensor 2
[205:204]	2	Temperature Sensor 3
[207:206]	2	Temperature Sensor 4
[209:208]	2	Temperature Sensor 5
[211:210]	2	Temperature Sensor 6
[213:212]	2	Temperature Sensor 7
[215:214]	2	Temperature Sensor 8
[219:216]	4	Thermal Management Temperature 1 Transition Count
[223:220]	4	Thermal Management Temperature 2 Transition Count
[227:224]	4	Total Time For Thermal Management Temperature 1
[231:228]	4	Total Time For Thermal Management Temperature 2
[511:232]	280	Reserved



7. PHYSICAL DIMENSION

7.1. BGA type 1620

Package: 16mm (x-axis) x 20mm (y-axis) / 0.8mm (Ball Pitch)

Table 7-1 BGA SSD Physical Dimensions and Weight

Capacity	Height (mm)	Width (mm)	length (mm)	Weight (gram)
64GB	1.15			0.67
128GB	1.15			0.67
256GB	1.15	16	20	0.67
512GB	1.35			0.84
1024GB	1.65]		1

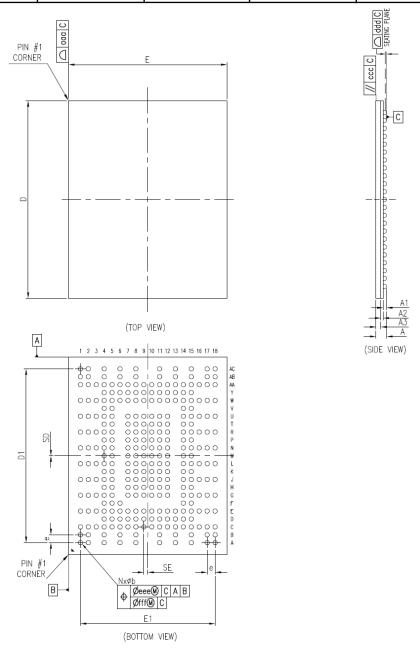


Figure 7-1 BGA type 1620 Package Outline Drawing



Table 7-2 Package Specification (Kioxia 112Layers 3D TLC x1/x2/x4 solution)

CVMDOL	DIMENSION IN MM		
2 IMPOL	MIN.	NOM.	MAX.
A	0.95	1.07	1.15
A1	0.30	0.35	0.40
A2		0.22	
A3		0.50	
D	20		
E	16		
	0.45		
	0.40		
Ь	0.40	0.45	0.50
е	0.80		31
N	291		
D1	5 17.60 BSC.		
(E10"	13.60 BSC.		
SD	0.00 BSC.		
SE	0.40 BSC.		
5	MO-216(REF.)		F.)
aaa	0.15		
ccc	0.20		
ddd	0.20		
BALL OFFSET(PACKAGE) eee 0.15		0.15	
fff	0.08		
	A1 A2 A3 D E b e N D1 E1 SD SE aaa ccc ddd eeee	SYMBOL MIN. A 0.95 A1 0.30 A2 A3 D E b 0.40 e N D1 1: E1 1: SD 0 SE 0 MO aaa ccc ddd eeee	SYMBOL MIN. NOM. A 0.95 1.07 A1 0.30 0.35 A2 0.22 A3 0.50 D 20 E 16 0.40 0.45 e 0.80 N 291 D1 17.60 BS E1 13.60 BS SD 0.00 BS SE 0.40 BS MO-216(RE 0.20 ddd 0.20 eee 0.15

NOTES:

- 1. All dimensions are in mm.
- $2. \hspace{0.5cm} \hbox{Ball designation is per JEP95, SECTION 3, SPP-010.} \\$
- 3. Fiducial Markings (Missing Fiducial location is A1 Corner Indicator).
- 4. A1 Triangle (orientation can vary and is non-critical).
- 5. DIM b is measured at the maximum solder ball diameter, parallel to primary datum Z.



Table 7-3 Package Specification (Kioxia 112Layers 3D TLC x8 solution)

1002	~ A	DIME	VSION IN	J MM
LY No.PS-MK-291-56001-**	SYMBOL	MIN.	NOM.	
TOTAL THICKNESS	Α	1.15 1.27 1.35		
STAND OFF	A1			0.40
SUBSTRATE THICKNESS	A2		0.22	
MOLD THICKNESS	А3		0.70	
DODY CITE	D	20		
BODY SIZE	E	16		
BALL DIAMETER		0.45		
BALL OPENING		0.40		
BALL WIDTH	Ь	0.40 0.45 0.50		0.50
BALL PITCH	е	0.80		
BALL COUNT	NO	291		
EDGE BALL CENTER TO CENTER	D1 A	17.60 BSC.		
EDGE DALL CENTER TO CENTER	EIL	13.60 BSC.		
BODY CENTER TO CONTACT BALL	SD	0.00 BSC.		
No ohle	SE	0.40 BSC.		
JEDEC(REF)		MO-216(REF.)		
PACKAGE EDGE TOLERANCE	aaa	0.15		
MOLD FLATNESS	ccc	0.20		
COPLANARITY	ddd	0.20		
BALL OFFSET(PACKAGE)	eee	0.15		
BALL OFFSET(BALL)	fff	0.08		

NOTES:

- 6. All dimensions are in mm.
- 7. Ball designation is per JEP95, SECTION 3, SPP-010.
- 8. Fiducial Markings (Missing Fiducial location is A1 Corner Indicator).
- 9. A1 Triangle (orientation can vary and is non-critical).
- 10. DIM b is measured at the maximum solder ball diameter, parallel to primary datum Z.



Table 7-4 Package Specification (Kioxia 112Layers 3D TLC x16 solution)

	at 1.7	U -	
SYMBOL	DIMENSION IN MM		
	MIN.	NOM.	MAX.
A	1.45	1.57	1.65
A1	0.30	0.35	0.40
A2		0.22	
A3		1.00	
D	20		
Е	16		
	0.45		
	0.40		
b	0.40 0.45 0.50		0.50
е	0.80		3.1
N	291		
D1	5 17.60 BSC.		
(E)10"	13.60 BSC.		
SD	0.00 BSC.		
SE	0.40 BSC.		
0	MO-216(REF.)		F.)
aaa	0.15		
ccc	0.20		
ddd	0.20		
eee	0.15		
fff	0.08		
	A A1 A2 A3 D E b e N D1 E1 SD SE aaa ccc ddd eee	SYMBOL MIN. A 1.45 A1 0.30 A2 A3 D E b 0.40 e N D1 1 E1 13 SD 0 SE 00 SE 00 MO aaa ccc ddd eee	SYMBOL MIN. NOM. A 1.45 1.57 A1 0.30 0.35 A2 0.22 A3 1.00 D 20 E 16 0.40 0.45 0.40 0.45 e 0.80 N 291 D1 17.60 BS E1 13.60 BS SD 0.00 BS SE 0.40 BS MO-216(RE 0.20 ddd 0.20 ddd 0.20 eee 0.15

NOTES:

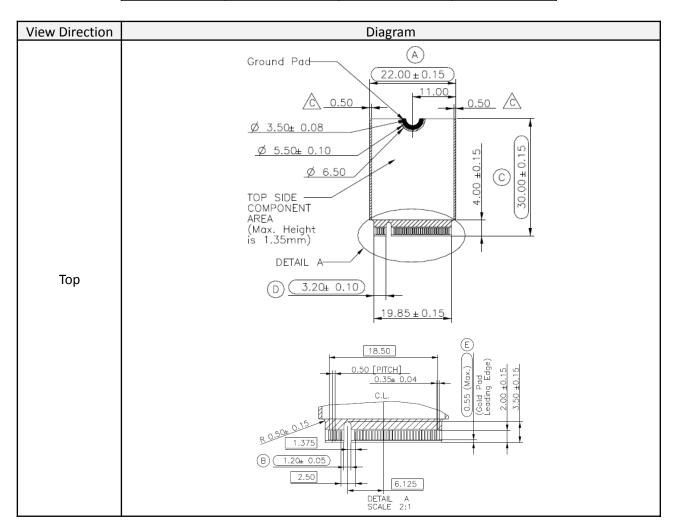
- 1. All dimensions are in mm.
- 2. Ball designation is per JEP95, SECTION 3, SPP-010.
- 3. Fiducial Markings (Missing Fiducial location is A1 Corner Indicator).
- 4. A1 Triangle (orientation can vary and is non-critical).
- 5. DIM b is measured at the maximum solder ball diameter, parallel to primary datum Z.



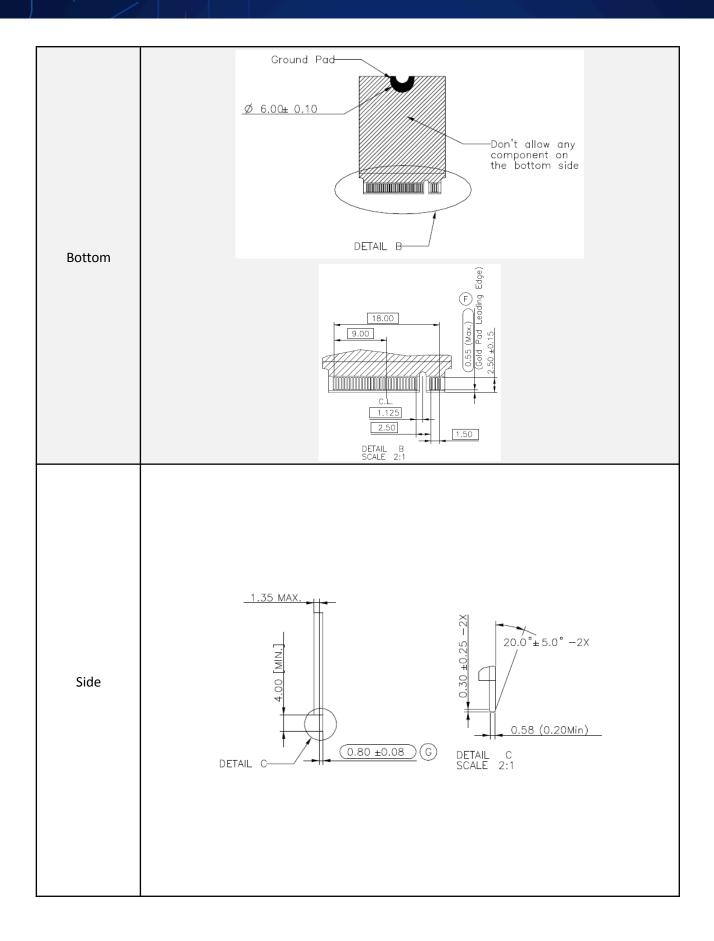
7.2. M.2 type 2230

Table 7-5 M.2 type 2230 Physical Dimensions

Capacity(GB)	Height (mm)	Width (mm)	Length (mm)
64			
128			
256	2.15±0.08	22±0.15	30±0.15
512			
1024			









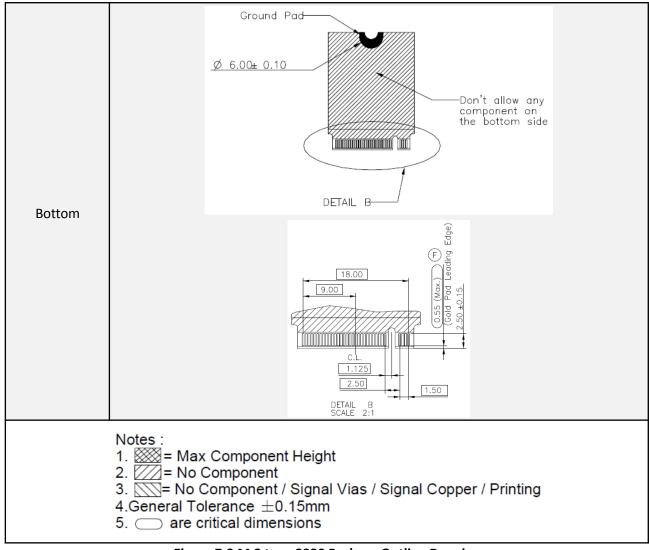


Figure 7-2 M.2 type 2230 Package Outline Drawing

8. APPLICATION NOTES

8.1. Wafer Level Chip Scale Packaging (WLCSP) Handling Precautions

There are a lot of components assembled on a single SSD device. Please handle the drive with care especially when it has any WLCSP (Wafer Level Chip Scale Packaging) components such as PMIC, thermal sensor or load switch. WLCSP is one of the packaging technologies that is widely adopted for making smaller footprints, but any bumps or scratches may damage those ultrasmall parts so gentle handling is strongly recommended.

A DO NOT DROP SSD

A INSTALL SSD WITH CARE

A STORE SSD IN A PROPER PACKAGE



8.2. M Key M.2 SSD Assembly Precautions

M Key M.2 SSD (Figure 1) is only compatible to M Key (Figure 2) socket. As shown in Use Case 2, misuse may cause severe damages to SSD including burn-out.

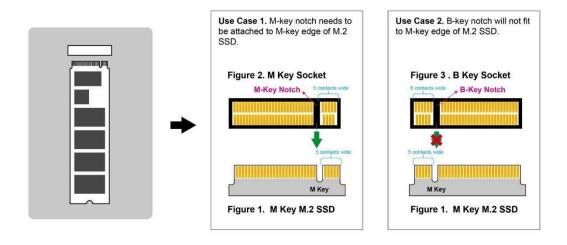


Figure 8-1 M Key M.2 Assembly Precautions



9. PRODUCT WARRANTY POLICY

For any other products manufactured and supplied by Phison ("Phison Products"), Phison hereby certify that in the event Phison Product does not conform to the specification for (A) a period instructed by Phison or mutually agreed by Phison and the customer in writing or (B) the period ending on the date at which customer's use of a Phison Product exceeds Phison Product's total Terabytes Written as recorded by or derived from Phison Product's S.M.A.R.T. Attribute, including but not limited to, Phison Product's drive life is used up in accordance with the S.M.A.R.T. Attribute, whichever occurs earlier("Warranty Period") and such inconformity is confirmed by Phison to be solely attributable to Phison, Phison agrees to repair or replace the nonconforming Phison Product, free of charge.

Notwithstanding the foregoing, the aforementioned warranty shall exclude the inconformity arising from, in relation to or associated with:

- (1) alternation, modification, improper use, misuse or excessive use of Phison Product;
- (2) failure to comply with Phison's instructions;
- (3) Phison's compliance with or use of the instructions, technologies, designs, specifications, devices, materials, components, parts, software and firmware provided, instructed or approved by Buyer (including any of its parents, subsidiaries, affiliates, suppliers, subcontractors or downstream customers);
- (4) combination of Phison Product with other materials, components, parts, goods, hardware, firmware or software not supplied by Phison;
- (5) any claim brought by a third party who is commonly known as intellectual property right assertion entity or patent troll;
- (6) NAND flash itself or NAND flash which is embedded into Phison Products;
- (7) Phison's compliance with general industry standards;
- (8) other error or failure not solely attributable to Phison's cause (including without limitation, normal wear or tear, manufacturing or assembly wastage, improper operation, virus, unauthorized maintenance or repair).

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THREATEN LIFE, INJURY, HEALTH, LOSS OF SIGNIFICANT AMOUNT OF MONEY ("CRITICAL USE"), AND BUYER AND USER HEREBY ASSUMES ALL RISK OF ANY CRITICAL USE OF PHISON PRODUCT.



10. REFERENCE

The following table is to list out the standards that have been adopted for designing the product.

Table 10-1 List of References

Title	Acronym/Source
	Restriction of Hazardous Substances Directive; for further
RoHS	information, please contact us at sales@phison.com or
	support@phison.com.
M.2	http://www.pcisig.com
PCI Express Base 4.0	https://www.pcisig.com/specifications/pciexpress/base4/
NVM Express Specification Rev. 1.4	http://www.nvmexpress.org/
Solid-State Drive Requirements and	http://www.iodoc.org/stordordo.documents/docs/iood210c
Endurance Test Method (JESD219A)	http://www.jedec.org/standards-documents/docs/jesd219a



11. TERMINOLOGY

The following table is to list out the acronyms that have been applied throughout the document.

Table 11-1 List of Terminology

	. 01
Term	Definitions
ATTO	Commercial performance benchmark application
DDR	Double data rate (SDRAM)
ASPM	Active states power management
APST	Autonomous power state transition
LBA	Logical block addressing
MB	Mega-byte
GB	Giga-byte
ТВ	Tera-byte
MTBF	Mean time between failures
PCIe	Pci express / peripheral component interconnect express
S.M.A.R.T.	Self-monitoring, analysis and reporting technology
SSD	Solid state disk